Features

- Supply Voltage 5 V
- Very Low Power Consumption 125 mW
- Very Good Image Rejection By Means of Phase Control Loop for Precise 90° Phase Shifting
- Duty-cycle Regeneration for Single-ended LO Input Signal
- Low LO Input Level -10 dBm
- LO Frequency from 70 MHz to 1 GHz
- Power-down Mode
- 25 dB Gain Control
 Very Low I/Q Output DC Offset Voltage Typically < 5 mV

Benefits

- Low Current Consumption
- Easy to Implement
- Perfect Performance for Large Variety of Wireless Applications

Electrostatic sensitive device. Observe precautions for handling.



Description

The silicon monolithic integrated circuit U2794B is a quadrature demodulator manufactured using Atmel's advanced UHF technology. This demodulator features a frequency range from 70 MHz to 1000 MHz, low current consumption, selectable gain, power-down mode and adjustment-free handling. The IC is suitable for direct conversion and image rejection applications in digital radio systems up to 1 GHz such as cellular radios, cordless telephones, cable TV and satellite TV systems.



1000-MHz Quadrature Demodulator

U2794B

Rev. 4653C-CELL-06/03





Figure 1. Block Diagram



Pin Configuration

Figure 2. Pinning SSO20



U2794B

Pin	Symbol	Function
1	IX	IX output
2	I	I output
3	II	II lowpass filter I
4	IIX	IIX lowpass filter I
5	Vs	Supply voltage
6	Vs	Supply voltage
7	RF _{in}	RF input
8	RFX _{in}	RFX input
9	QQ	QQ lowpass filter Q
10	QQX	QQX lowpass filter Q
11	GC	GC gain control
12	PCX	PCX phase control
13	PC	PC phase control
14	PU	PU power up
15	LOX _{in}	LOX input
16	GND	Ground
17	LO _{in}	LO input
18	GND	Ground
19	Q	Q output
20	QX	QX output

Pin Description





Absolute Maximum Ratings

Parameters	Symbol	Value	Unit
Supply voltage	V _S	6	V
Input voltage	V _i	0 to V _S	V
Junction temperature	Tj	+125	°C
Storage-temperature range	T _{stg}	-40 to +125	°C

Thermal Resistance

Parameters	Symbol	Value	Unit
Junction ambient SSO20	R _{thJA}	140	K/W

Operating Range

Parameters	Symbol	Value	Unit
Supply-voltage range	V _S	4.75 to 5.25	V
Ambient-temperature range	T _{amb}	-40 to +85	°C

Electrical Characteristics

Test conditions (unless otherwise specified); $V_S = 5 \text{ V}$, $T_{amb} = 25^{\circ}\text{C}$, referred to test circuit System impedance $Z_O = 50 \Omega$, fiLO = 950 MHz, PiLO = -10 dBm

No.	Parameters	Test Conditions	Pin	Symbol	Min.	Тур.	Max.	Unit	Type*
1.1	Supply-voltage range		5, 6	Vs	4.75		5.25	V	A
1.2	Supply current		5, 6	۱ _s	22	30	35	mA	A
2	Power-down Mode								
2.1	"OFF" mode supply	$V_{PU} \le 0.5 V$	14, 5	I _{SPU}		≤ 1		μA	В
	current	V _{PU} = 1.0 V	6			20		μA	D
		(1)							
3	Switch Voltage								
3.1	"Power ON"		14	V _{PON}	4			V	D
*)									

*) Type means: A = 100% tested, B = 100% correlation tested, C = Characterized on samples, D = Design parameter

- Notes: 1. During power-down status a load circuitry with DC-isolation to GND is assumed, otherwise a current of I ≈ (VS -0.8 V)/RI has to be added to the above power-down current for each output I, IX, Q, QX.
 - 2. The required LO-Level is a function of the LO frequency (see Figure 8).
 - 3. Measured with input matching. For 950 MHz, the optional transmission line T3 at the RF input may be used for this purpose. Noise figure measurements without using the differential output signal result in a worse noise figure.
 - 4. Using Pins 7 and 8 as a symmetric RF input, the second-order IIP can be improved.
 - 5. Due to test board parasitics, this bandwidth may be reduced and not be equal for I, IX, Q, QX. If symmetry and full bandwidth is required, the lowpass Pins 3, 4 and 9, 10 should be isolated from the board. the bandwidth of the I/Q outputs can be increased further by using a resistor between Pins 3, 4, 9 and 10. These resistors shunt the internal loads of RI ~ 5.4 kΩ. The decrease in gain here has to be considered.
 - 6. The internal current of the output emitter followers is 0.6 mA. This reduces the undistorted output voltage swing at a 50 Ω load to approximately 30 mV. For low signal distortion the load impedance should be RI \geq 5 k Ω .
 - 7. Referred to the level of the output vector $\sqrt{l^2 + Q^2}$
 - 8. The low-gain status is achieved with an open or high-ohmic Pin 11. A recommended application circuit for switching between high and low gain status is hown in Figure 3.

U2794B

Electrical Characteristics (Continued)

Test conditions (unless otherwise specified); $V_S = 5 \text{ V}$, $T_{amb} = 25^{\circ}\text{C}$, referred to test circuit System impedance $Z_O = 50 \Omega$, fiLO = 950 MHz, PiLO = -10 dBm

No.	Parameters	Test Conditions	Pin	Symbol	Min.	Тур.	Max.	Unit	Type*
3.2	"Power DOWN"		14	V _{POFF}			1	V	D
4	LO Input, LO _{in}								
4.1	Frequency range		17	f _{iLO}	70		1000	MHz	D
4.2	Input level	(2)	17	P _{iLO}	-12	-10	-5	dBm	D
4.3	Input impedance	See Figure 12	17	Z _{iLO}		50		Ω	D
4.4	Voltage standing wave ratio	See Figure 5	17	VSWR _{LO}		1.2	2		D
4.5	Duty-cycle range		17	DCR _{LO}	0.4		0.6		D
5	RF Input, RF _{in}				•	•			
5.1	Noise figure (DSB) symmetrical output	at 950 MHz ⁽³⁾ at 100 MHz	7, 8	NF		12 10		dB	D
5.2	Frequency range	$f_{iRF} = Fi_{LO} \pm BW_{YQ}$	7, 8	f _{iRF}	40		1030	MHz	D
5.3	-1 dB input compression point	High gain Low gain	7, 8	P _{1dBHG} P _{1dBLG}		-8 +3.5		dBm	D
5.4	Second order IIP	(4)	7, 8	IIP _{2HG}		35		dBm	D
5.5	Third order IIP	High gain Low gain	7, 8	IIP _{3HG} IIP _{3LG}		+3 +13		dBm	D
5.6	LO leakage	Symmetric input Asymmetric input	7, 8	L _{OL}		≤ -60 ≤ -55		dBm	D
5.7	Input impedance	see Figure 12	7, 8	Z _{iRF}		500110.8		ΩllpF	D
6	I/Q Outputs (I, IX, Q, QX) Emitter Follower I = 0.6 mA								
6.1	3–dB bandwidth w/o external C		1, 2, 19, 20	BWI/Q	≥ 30			MHz	D
6.2	I/Q amplitude error		1, 2, 19, 20	Ae	-0.5	≤±0.2	+0.5	dB	В
6.3	I/Q phase error		1, 2, 19, 20	Pe	-3	≤±1.5	+3	Deg	В

*) Type means: A = 100% tested, B = 100% correlation tested, C = Characterized on samples, D = Design parameter

Notes: 1. During power-down status a load circuitry with DC-isolation to GND is assumed, otherwise a current of I ≈ (VS -0.8 V)/RI has to be added to the above power-down current for each output I, IX, Q, QX.

- 2. The required LO-Level is a function of the LO frequency (see Figure 8).
- 3. Measured with input matching. For 950 MHz, the optional transmission line T3 at the RF input may be used for this purpose. Noise figure measurements without using the differential output signal result in a worse noise figure.
- 4. Using Pins 7 and 8 as a symmetric RF input, the second-order IIP can be improved.
- 5. Due to test board parasitics, this bandwidth may be reduced and not be equal for I, IX, Q, QX. If symmetry and full bandwidth is required, the lowpass Pins 3, 4 and 9, 10 should be isolated from the board. the bandwidth of the I/Q outputs can be increased further by using a resistor between Pins 3, 4, 9 and 10. These resistors shunt the internal loads of RI ~ 5.4 kΩ. The decrease in gain here has to be considered.
- 6. The internal current of the output emitter followers is 0.6 mA. This reduces the undistorted output voltage swing at a 50 Ω load to approximately 30 mV. For low signal distortion the load impedance should be RI \geq 5 k Ω .
- 7. Referred to the level of the output vector $\sqrt{I^2 + Q^2}$
- 8. The low-gain status is achieved with an open or high-ohmic Pin 11. A recommended application circuit for switching between high and low gain status is hown in Figure 3.





Electrical Characteristics (Continued)

Test conditions (unless otherwise specified); $V_S = 5 \text{ V}$, $T_{amb} = 25^{\circ}\text{C}$, referred to test circuit System impedance $Z_O = 50 \Omega$, fiLO = 950 MHz, PiLO = -10 dBm

No.	Parameters	Test Conditions	Pin	Symbol	Min.	Тур.	Max.	Unit	Type*
6.4	I/Q maximum output swing	Symm. output $R_L > 5 k\Omega$	1, 2, 19, 20	V _{PP}			2		D
6.5	DC output voltage		1, 2, 19, 20	V _{OUT}	2.5	2.8	3.1	V	A
6.6	DC output offset voltage	(6)	1, 2, 19, 20	V _{offset}		< 5		mV	Test Spec.
6.7	Output impedance	see Figure 12	1, 2, 19, 20	Z _{out}		50		Ω	D
7	Gain Control, GC								
7.1	Control range power	(7)	11	GCR		25		dB	D
	Gain high			G _H		23		dBm	В
	Gain low			GL		-2		dBm	D
7.2	Switch Voltage								
7.3	"Gain high"		11				1	V	
7.4	"Gain Iow"	(8)	11 < open						
7.5	Settling Time, ST								
7.6	Power "OFF" - "ON"			T_{SON}		< 4		μs	D
7.7	Power "ON" - "OFF"			T _{SOFF}		< 4		μs	D

*) Type means: A = 100% tested, B = 100% correlation tested, C = Characterized on samples, D = Design parameter

Notes: 1. During power-down status a load circuitry with DC-isolation to GND is assumed, otherwise a current of I ≈ (VS -0.8 V)/RI has to be added to the above power-down current for each output I, IX, Q, QX.

2. The required LO-Level is a function of the LO frequency (see Figure 8).

3. Measured with input matching. For 950 MHz, the optional transmission line T3 at the RF input may be used for this purpose. Noise figure measurements without using the differential output signal result in a worse noise figure.

- 4. Using Pins 7 and 8 as a symmetric RF input, the second-order IIP can be improved.
- 5. Due to test board parasitics, this bandwidth may be reduced and not be equal for I, IX, Q, QX. If symmetry and full bandwidth is required, the lowpass Pins 3, 4 and 9, 10 should be isolated from the board. the bandwidth of the I/Q outputs can be increased further by using a resistor between Pins 3, 4, 9 and 10. These resistors shunt the internal loads of RI ~ 5.4 kΩ. The decrease in gain here has to be considered.

6. The internal current of the output emitter followers is 0.6 mA. This reduces the undistorted output voltage swing at a 50 Ω load to approximately 30 mV. For low signal distortion the load impedance should be RI \ge 5 k Ω .

- 7. Referred to the level of the output vector $\sqrt{l^2 + Q^2}$
- 8. The low-gain status is achieved with an open or high-ohmic Pin 11. A recommended application circuit for switching between high and low gain status is hown in Figure 3.

Figure 3. Test Circuit



* optional for single-ended tests (notice 3 dB bandwidth of AD620) T1, T2 = transmission line Z_O = 50 $\Omega.$

If no GC function is required, connect Pin 11 to GND.

For high and low gain status GC' is to be switched to GND respectively to V_s.

Figure 4. I and Q phase for $f_{RF} > f_{LO}$. For $f_{RF} < f_{LO}$ the phase is inverted.







Figure 5. Typical VSWR Frequency Response of the LO Input



Figure 6. Noise Figure versus LO Frequency; o: Value at 950 MHz with RF Input Matching with T3



Figure 7. Typical Suitable LO Power Range versus Frequency



U2794B





Figure 9. Typical Output Signal versus LO Frequency for P_{RF} = -15 dBm and PLO = -15 dBm



Figure 10. Typical Suitable LO Power Range versus Frequency







Figure 11. Typical Output Voltage (single ended) versus P_{RF} at T_{amb} = 25°C and PLO = -15 dBm



Figure 12. Typical S11 Frequency Response



a: LO input, LO frequency from 100 MHz to 1100 MHz, marker: 950 MHz b: RF input, RF frequency from 100 MHz to 1100 MHz, marker: 950 MHz c: I/Q Outputs, Baseband Frequency from 5 MHz to 55 MHz, marker: 25 MHz

Figure 13. Evaluation Board Layout



Figure 14. Evaluation Board







External Components

	CUCC	100 nF	
	CRFX	1 nF	
	CLO	100 pF	
	CNLO	1 nF	
	CRF	100 pF	
	CII, CQQ		optional external lowpass filters
	Т3		transmission line for RF-input matching, to connect optionally
	CI, CIX		optional for AC-coupling at
	CQ, CQX		baseband outputs
	CPDN	100 pF	not connected
	CGC	100 pF	
	CPC	100 pF	not connected
	CNPC	100 pF	not connected
	GSW		gain switch
Calibration Part			
	CO, CS, CL RL	100 pF 50 Ω	
Conversion to Single Ended Output	(see data shee	et of AD620)	
	OP1, OP2		AD620
	RG1, RG2		prog. gain, see datasheet, for 5.6 k Ω a gain of 1 at 50 Ω is achieved together with RD1 and RD2.
	RD1, RD2	450 Ω	-
	CS1, CS2	100 nF	
	CS3, CS4	100 nF	

Description of the Evaluation Board

Board material: epoxy; ϵr = 4.8, thickness = 0.5 mm, transmission lines: Z_{O} = 50 Ω

The board offers the following functions:

- Test circuit for the U2794B:
 - The supply voltage and the control inputs GC, PC and PU are connected via a plug strip. The control input voltages can be generated via external potentiometers; then the inputs should be AC-grounded (time requirements in burst mode for power up have to be considered).
 - The outputs I, IX, Q, QX are DC coupled via an plug strip or can be ACconnected via SMB plugs for high frequency tests e.g. noise figure or sparameter measurement. The Pins II, IIX, QQ, QQX allow user-definable filtering with 2 external capacitors CII, CQQ.
 - The offsets of both channels can be adjusted with two potentimeters or resistors.
 - The LO- and the RF-inputs are AC-coupled and connected via SMB plugs. If transmission line T3 is connected to the RF-input and AC-grounded at the other end, gain and noise performance can be improved (input matching to 50 Ω).
 - The complementary RF-input is AC-coupled to GND (CRFX = 1 nF), the same appears to the complementary LO input (CNLO = 1 nF).
- A calibration part which allows to calibrate an s-parameter analyzer directly to the inand output- signal ports of the U2794B.
- For single-ended measurements at the demodulator outputs, two OPs (e.g., AD620 or other) can be con-figured with programmable gain; together with an output-divider network RD = 450 Ω to RL = 50 Ω, direct measurements with 50 Ω load impedances are possible at frequencies t < 100 kHz.





Ordering Information

Extended Type Number	Package	Remarks
U2794B-MFS	SSO20	Tube, MOQ 830 pcs
U2794B-MFSG3	SSO20	Taped and reeled, MOQ 4000 pcs

Package Information





Atmel Headquarters

Corporate Headquarters 2325 Orchard Parkway San Jose, CA 95131 TEL 1(408) 441-0311 FAX 1(408) 487-2600

Europe

Atmel Sarl Route des Arsenaux 41 Case Postale 80 CH-1705 Fribourg Switzerland TEL (41) 26-426-5555 FAX (41) 26-426-5500

Asia

Room 1219 Chinachem Golden Plaza 77 Mody Road Tsimhatsui East Kowloon Hong Kong TEL (852) 2721-9778 FAX (852) 2722-1369

Japan

9F, Tonetsu Shinkawa Bldg. 1-24-8 Shinkawa Chuo-ku, Tokyo 104-0033 Japan TEL (81) 3-3523-3551 FAX (81) 3-3523-7581

Atmel Operations

Memory

2325 Orchard Parkway San Jose, CA 95131 TEL 1(408) 441-0311 FAX 1(408) 436-4314

Microcontrollers

2325 Orchard Parkway San Jose, CA 95131 TEL 1(408) 441-0311 FAX 1(408) 436-4314

La Chantrerie BP 70602 44306 Nantes Cedex 3, France TEL (33) 2-40-18-18-18 FAX (33) 2-40-18-19-60

ASIC/ASSP/Smart Cards

Zone Industrielle 13106 Rousset Cedex, France TEL (33) 4-42-53-60-00 FAX (33) 4-42-53-60-01

1150 East Cheyenne Mtn. Blvd. Colorado Springs, CO 80906 TEL 1(719) 576-3300 FAX 1(719) 540-1759

Scottish Enterprise Technology Park Maxwell Building East Kilbride G75 0QR, Scotland TEL (44) 1355-803-000 FAX (44) 1355-242-743

RF/Automotive

Theresienstrasse 2 Postfach 3535 74025 Heilbronn, Germany TEL (49) 71-31-67-0 FAX (49) 71-31-67-2340

1150 East Cheyenne Mtn. Blvd. Colorado Springs, CO 80906 TEL 1(719) 576-3300 FAX 1(719) 540-1759

Biometrics/Imaging/Hi-Rel MPU/

High Speed Converters/RF Datacom Avenue de Rochepleine BP 123 38521 Saint-Egreve Cedex, France TEL (33) 4-76-58-30-00 FAX (33) 4-76-58-34-80

e-mail literature@atmel.com

Web Site http://www.atmel.com

© Atmel Corporation 2003.

Atmel Corporation makes no warranty for the use of its products, other than those expressly contained in the Company's standard warranty which is detailed in Atmel's Terms and Conditions located on the Company's web site. The Company assumes no responsibility for any errors which may appear in this document, reserves the right to change devices or specifications detailed herein at any time without notice, and does not make any commitment to update the information contained herein. No licenses to patents or other intellectual property of Atmel are granted by the Company in connection with the sale of Atmel products, expressly or by implication. Atmel's products are not authorized for use as critical components in life support devices or systems.

Atmel[®] is the registered trademark of Atmel.

Other terms and product names may be the trademarks of others.

